



International
Standard

ISO 21068-4

**Chemical analysis of raw materials
and refractory products containing
silicon-carbide, silicon-nitride,
silicon-oxynitride and sialon —**

**Part 4:
XRD methods**

*Analyse chimique des matières premières et des produits
réfractaires contenant du carbure de silicium, du nitrure de
silicium, de l'oxynitride de silicium et du SiAlON —*

Partie 4: Méthodes de DRX

**First edition
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Foreword

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This document was prepared by Technical Committee ISO/TC 33, *Refractories*, in collaboration with the European Committee for Standardization (CEN) Technical Committee CEN/TC 187, *Refractory products and materials*, in accordance with the Agreement on technical cooperation between ISO and CEN (Vienna Agreement).

A list of all parts in the ISO 21068 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

The ISO 21068 series has been developed from the combination of EN 12698-1:2007^[1] and EN 12698-2:2007^[2] and ISO 21068-1:2008,^[3] ISO 21068-2:2008^[4] and ISO 21068-3:2008.^[5] The last three standards have been originally developed from the combination of Japanese standard JIS R 2011:2007^[6] and work items developed within CEN. Because there is a wide variety of laboratory equipment in use, the most commonly used methods are described.

This document is derived from EN 12698-2:2007^[2] describing XRD methods for the determination of mineralogical phases typically apparent in nitride and oxy-nitride bonded silicon carbide refractory products using a Bragg-Brentano diffractometer.

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